

FIG. 1

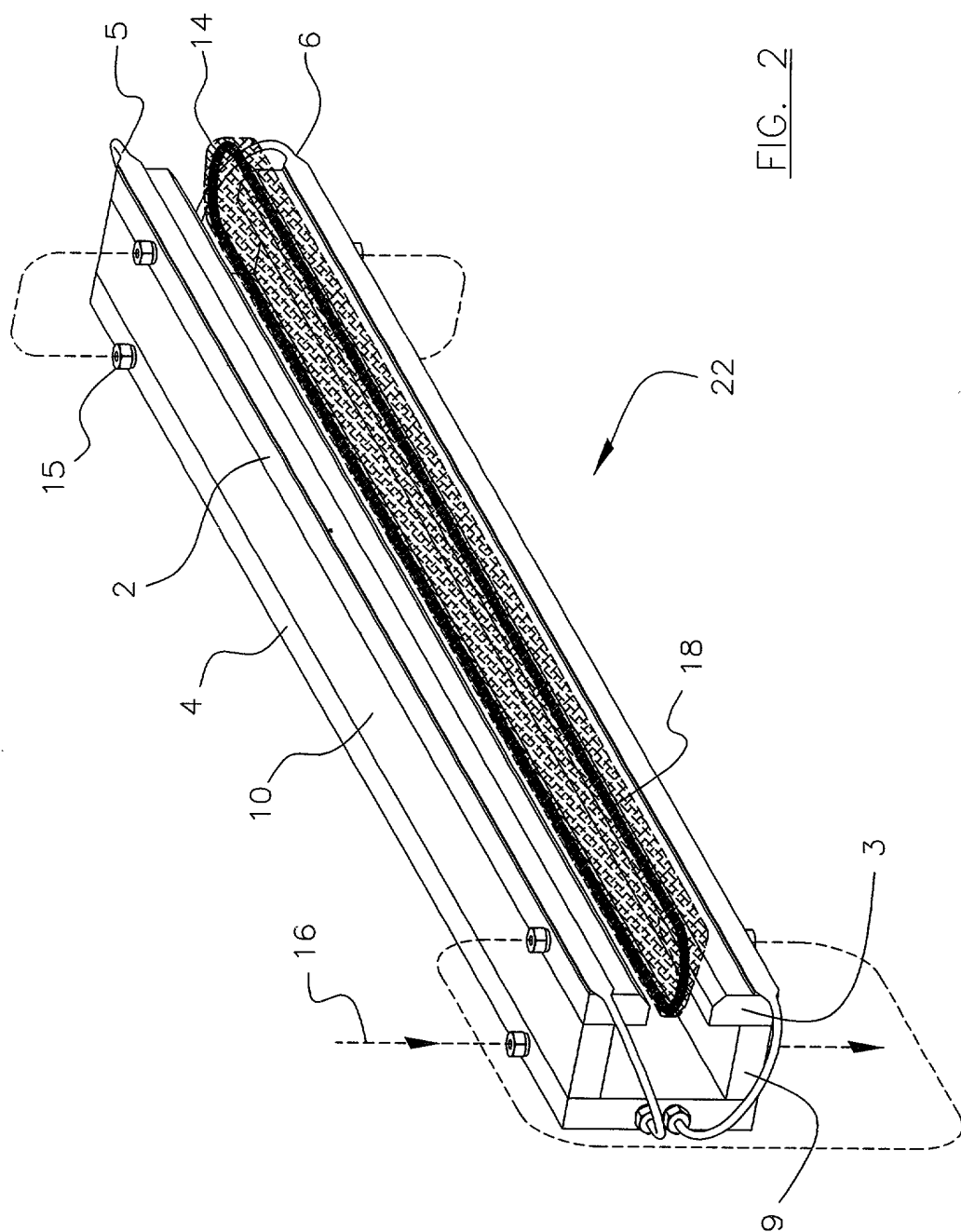


FIG. 2

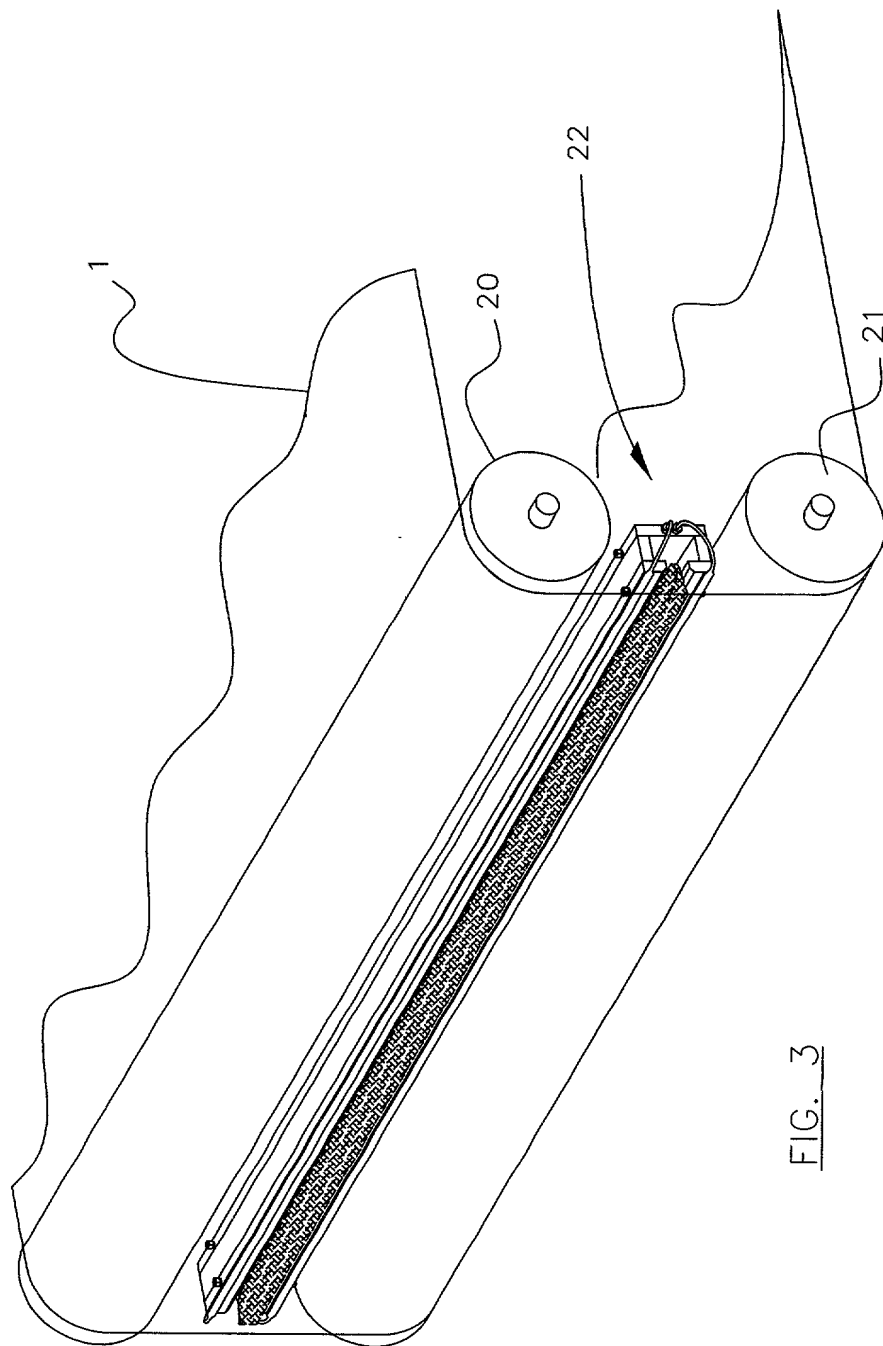


FIG. 3

FIG. 4 is a perspective view of the device 100 in a closed position. The device 100 includes a housing 102 and a display 104. The housing 102 is formed by a top cover 106 and a bottom cover 108. The display 104 is mounted on the top cover 106. The device 100 is shown in a closed position, with the display 104 folded down against the top cover 106. The device 100 is shown in a perspective view, with the top cover 106 and the bottom cover 108 visible. The display 104 is shown in a perspective view, with the top cover 106 and the bottom cover 108 visible. The device 100 is shown in a perspective view, with the top cover 106 and the bottom cover 108 visible. The display 104 is shown in a perspective view, with the top cover 106 and the bottom cover 108 visible.

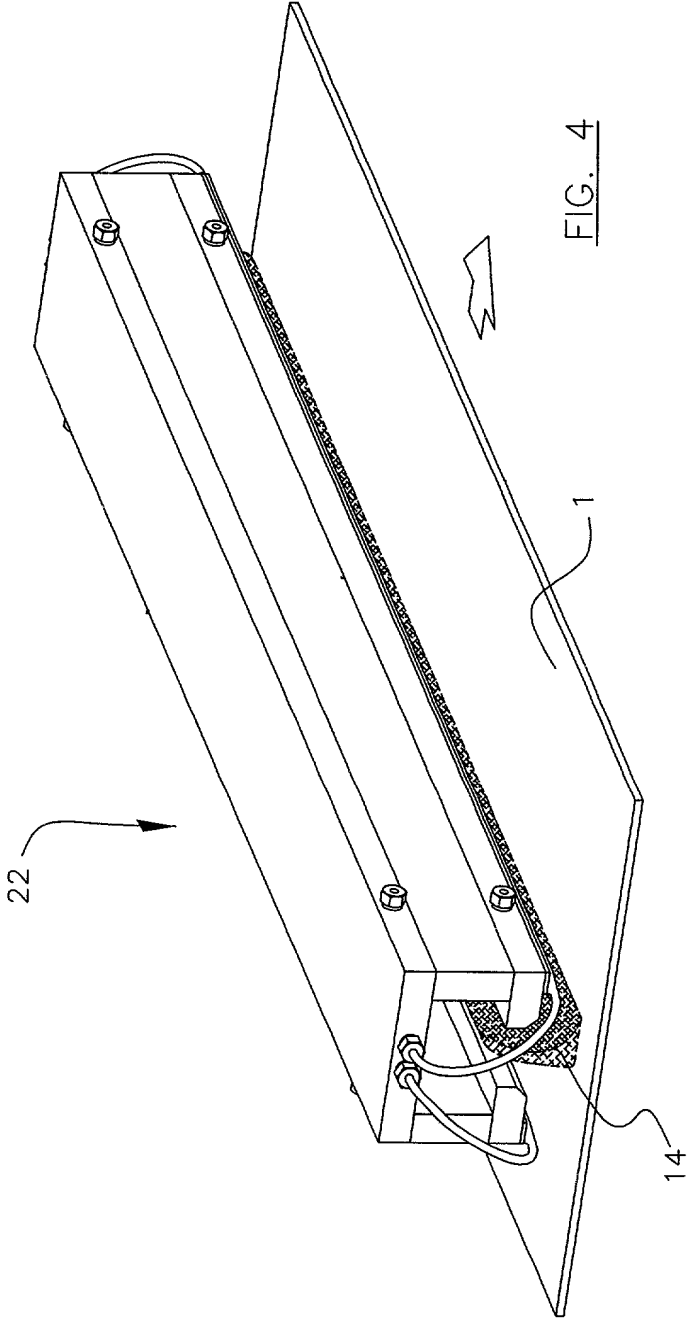


FIG. 4



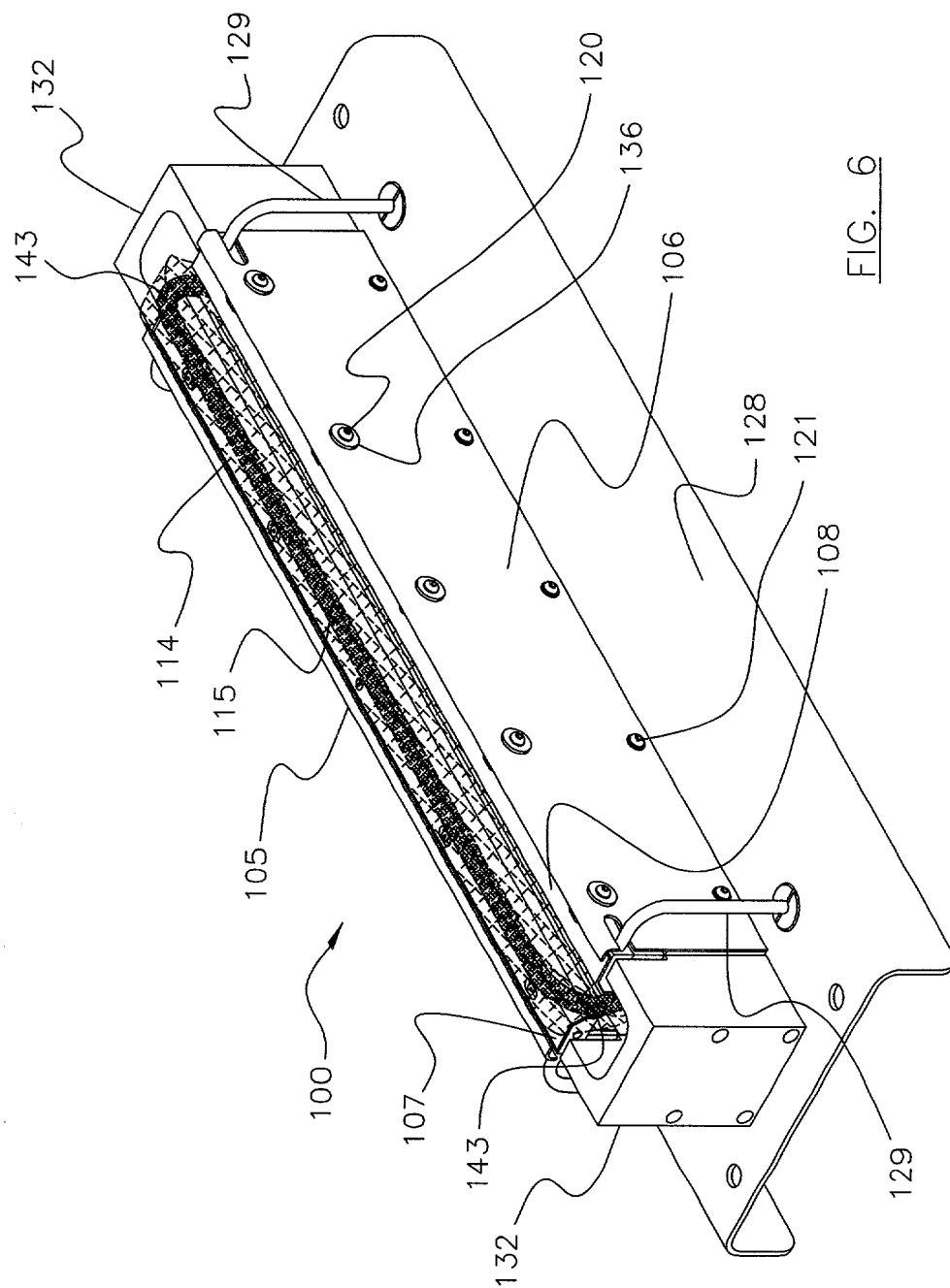


FIG. 6

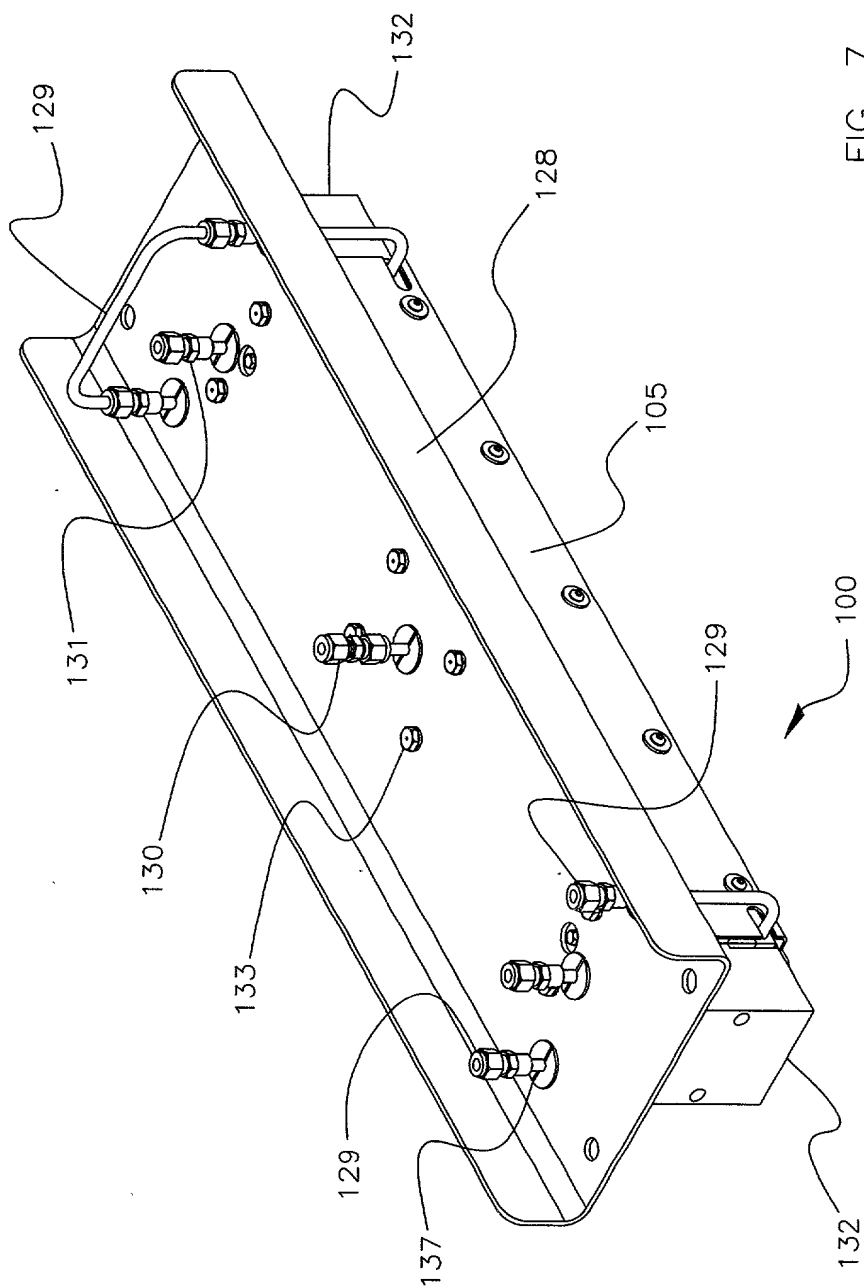


FIG. 7

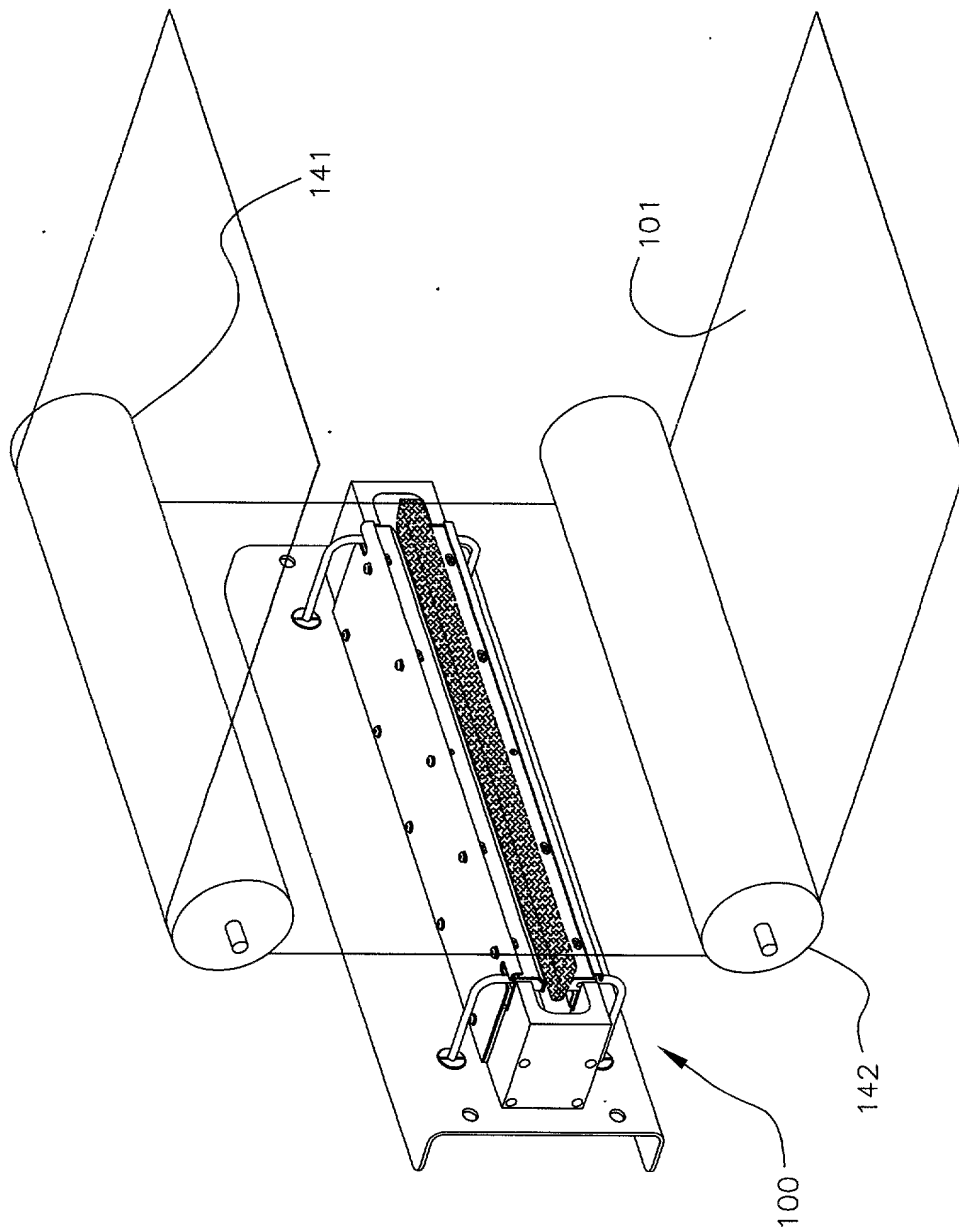


FIG. 8





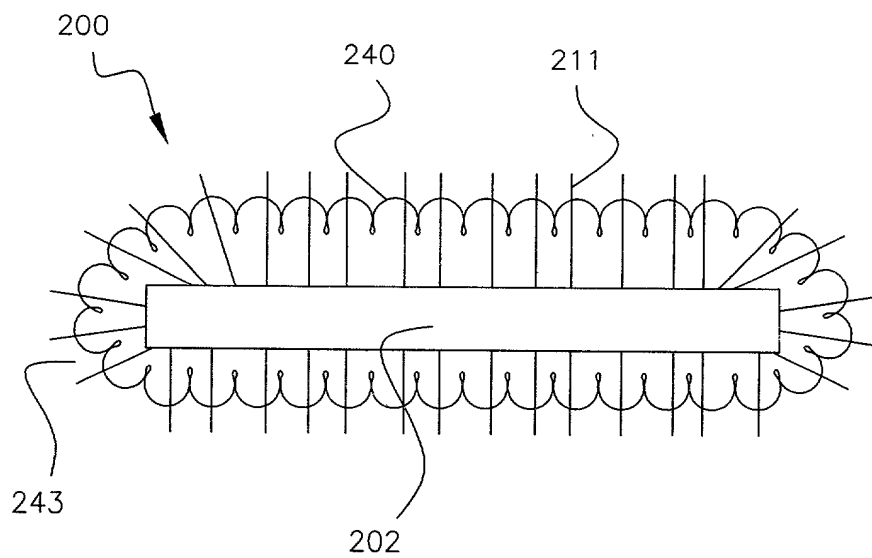


FIG. 10

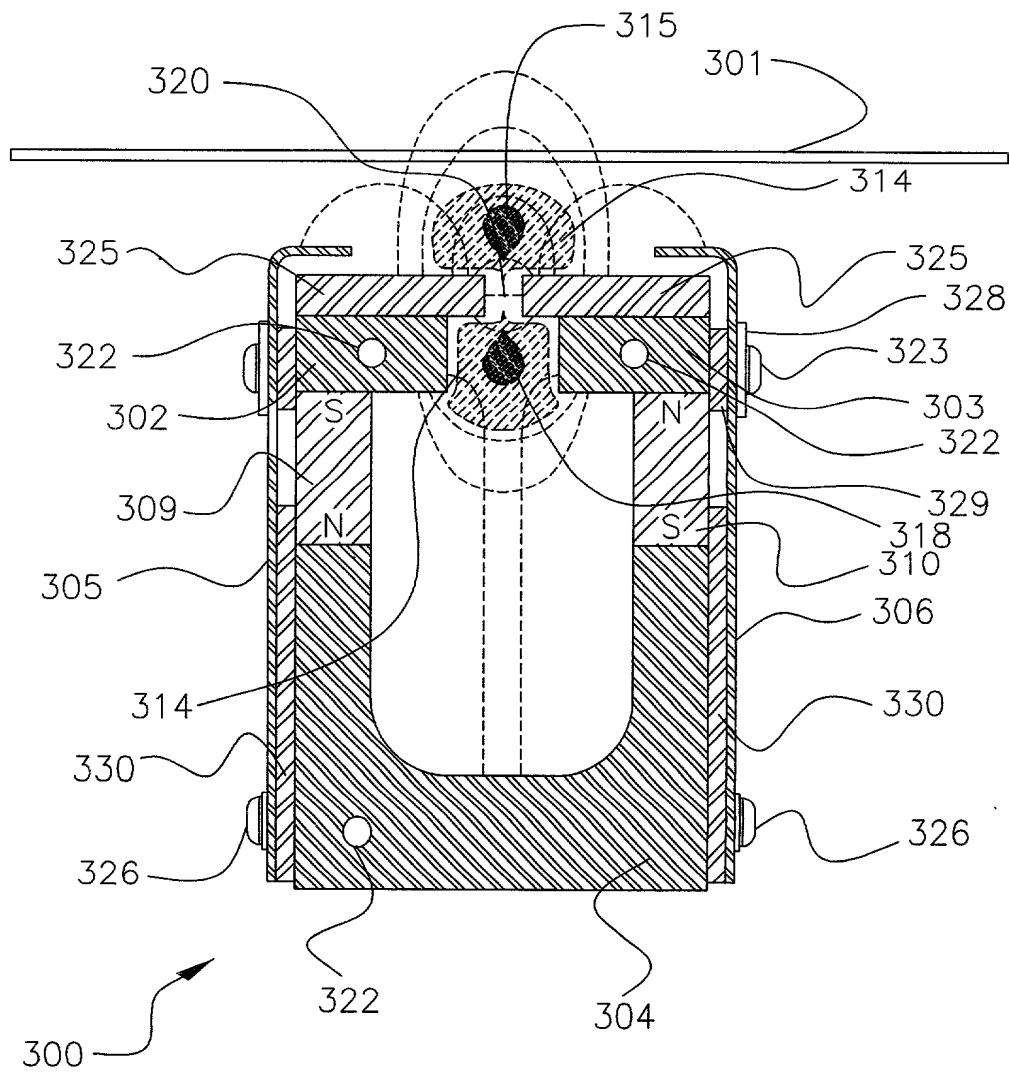


FIG. 11

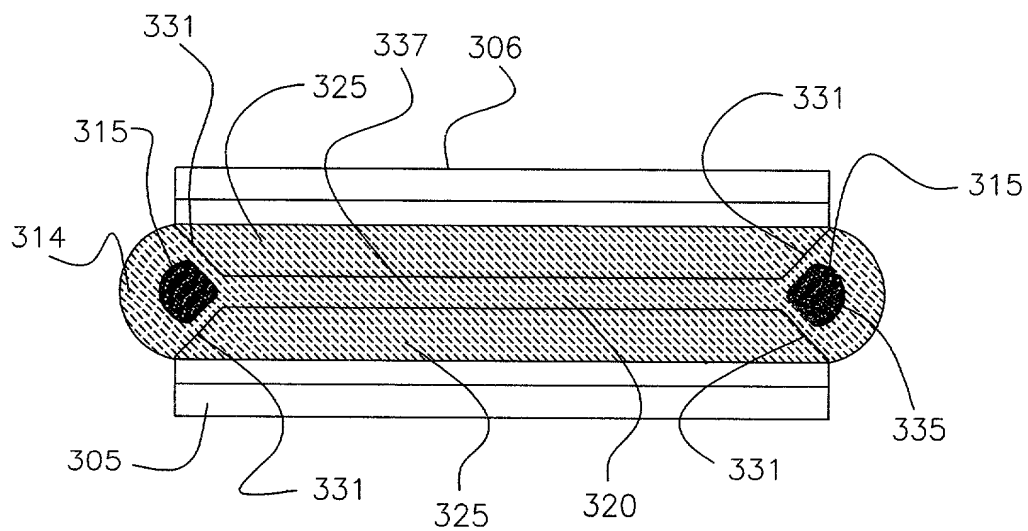


FIG. 12







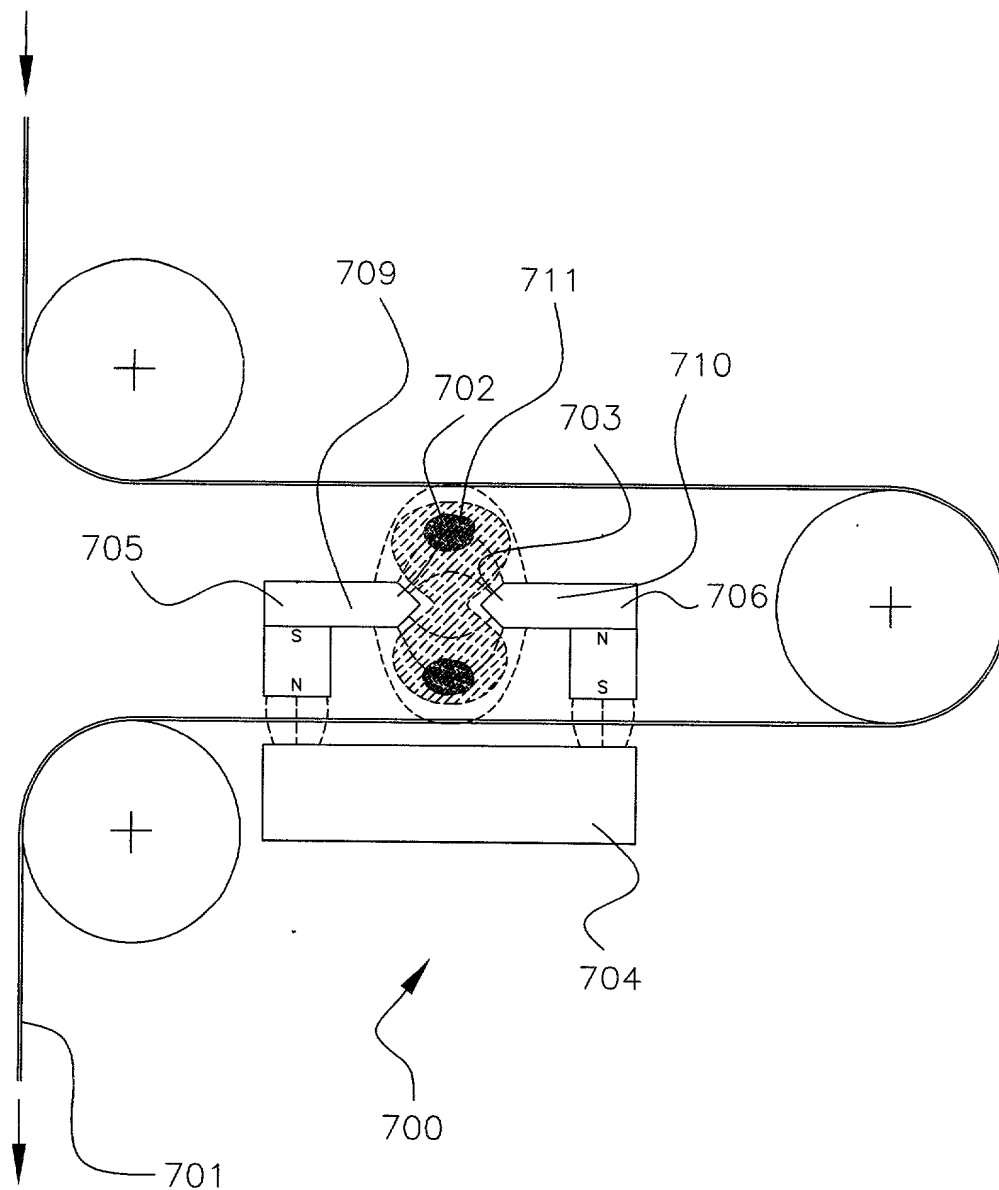


FIG. 16



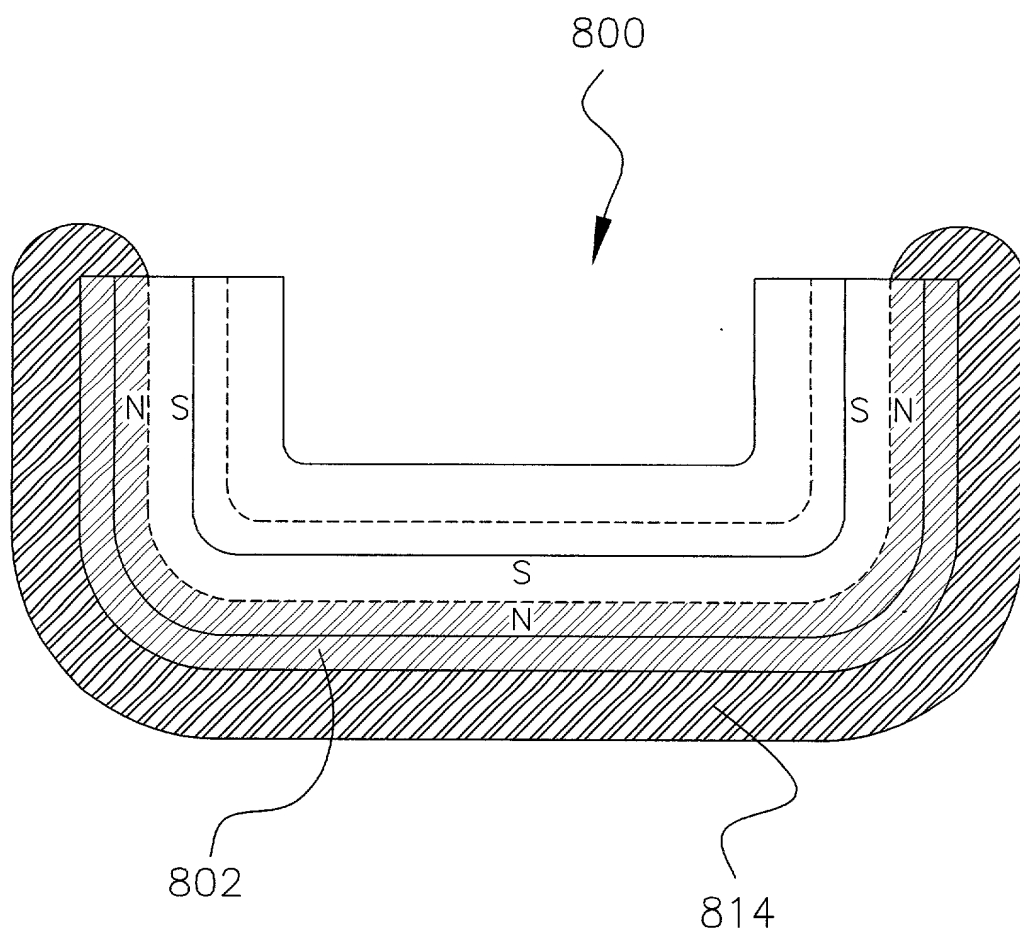


FIG. 17

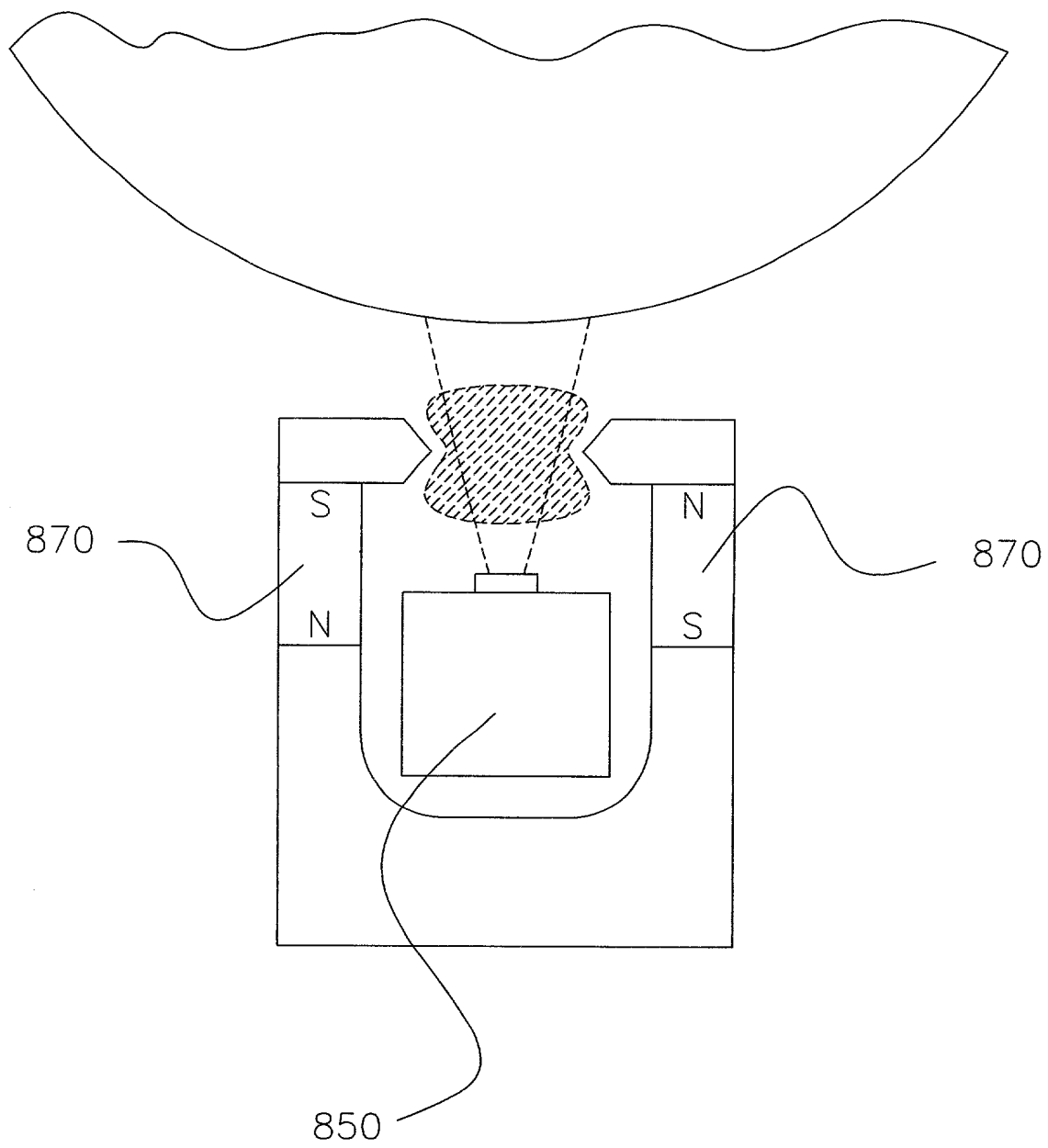


FIG. 18

FIG. 19 is a schematic diagram of a system 860 for testing a device 862. The system 860 includes a base 864 and a support structure 866. The support structure 866 includes a central column 868 and two side columns 870 and 872. The central column 868 includes a top section 874 and a bottom section 876. The side columns 870 and 872 include top sections 878 and 880 and bottom sections 882 and 884. The device 862 is positioned between the top sections 874 and 878. The device 862 includes a top surface 886 and a bottom surface 888. The top surface 886 is in contact with the top section 874 of the central column 868. The bottom surface 888 is in contact with the bottom section 876 of the central column 868. The device 862 also includes a left side surface 890 and a right side surface 892. The left side surface 890 is in contact with the top section 878 of the side column 870. The right side surface 892 is in contact with the top section 880 of the side column 872. The device 862 is supported by the support structure 866. The support structure 866 is used to hold the device 862 in a fixed position for testing. The system 860 is used to test the device 862 under various conditions. The system 860 is a schematic diagram of a system 860 for testing a device 862. The system 860 includes a base 864 and a support structure 866. The support structure 866 includes a central column 868 and two side columns 870 and 872. The central column 868 includes a top section 874 and a bottom section 876. The side columns 870 and 872 include top sections 878 and 880 and bottom sections 882 and 884. The device 862 is positioned between the top sections 874 and 878. The device 862 includes a top surface 886 and a bottom surface 888. The top surface 886 is in contact with the top section 874 of the central column 868. The bottom surface 888 is in contact with the bottom section 876 of the central column 868. The device 862 also includes a left side surface 890 and a right side surface 892. The left side surface 890 is in contact with the top section 878 of the side column 870. The right side surface 892 is in contact with the top section 880 of the side column 872. The device 862 is supported by the support structure 866. The support structure 866 is used to hold the device 862 in a fixed position for testing. The system 860 is used to test the device 862 under various conditions.

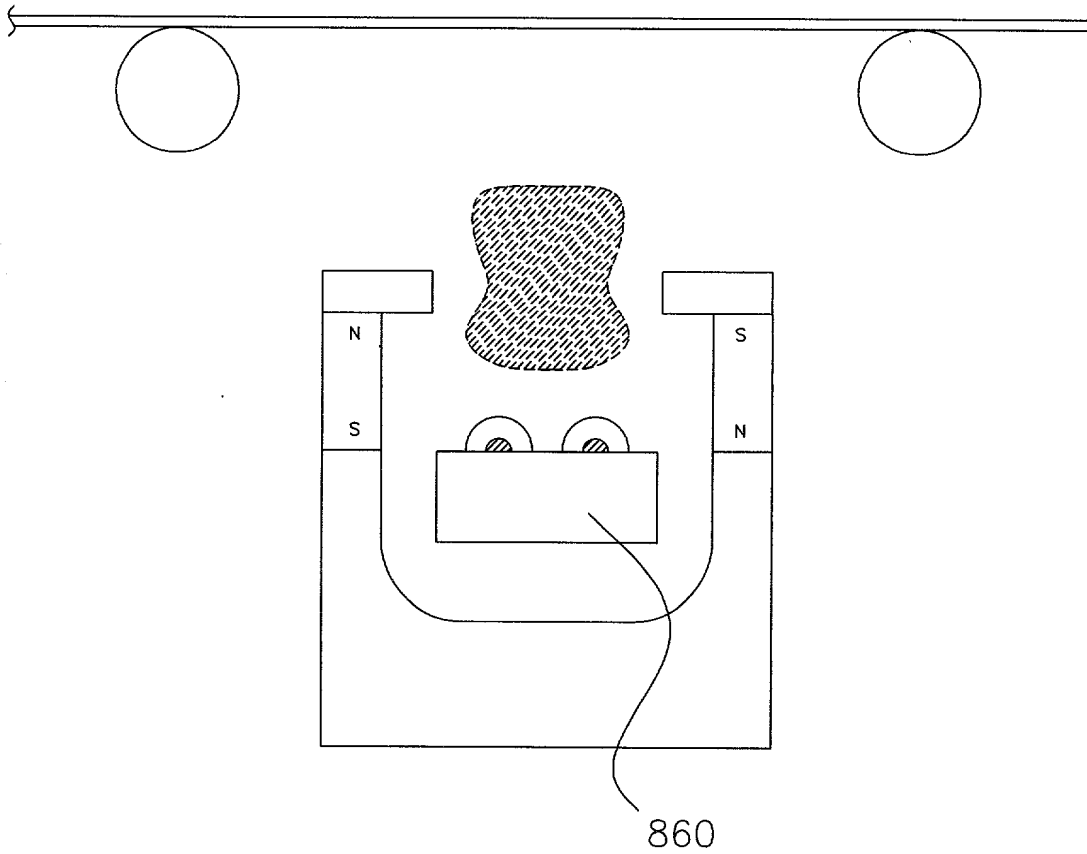


FIG. 19

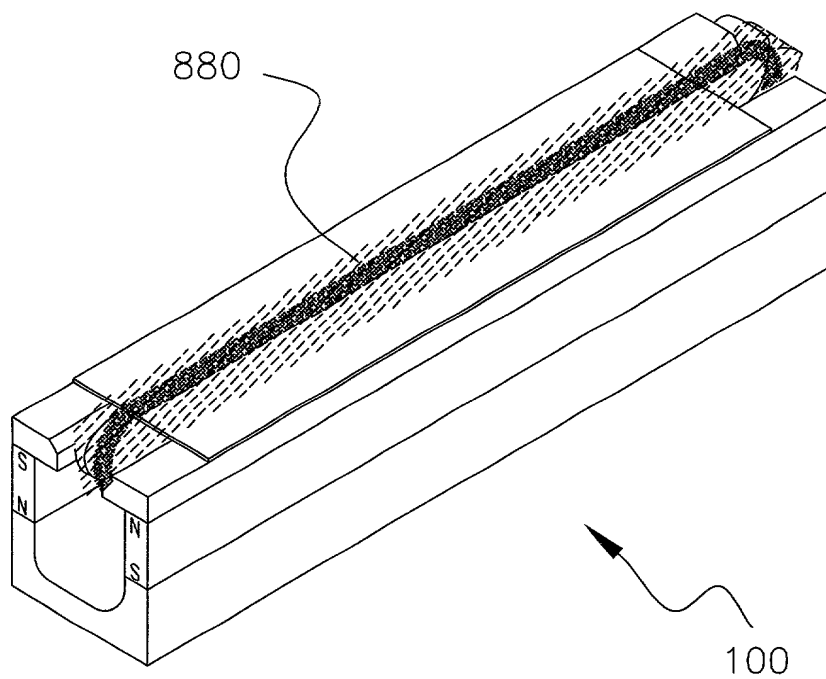


FIG. 20

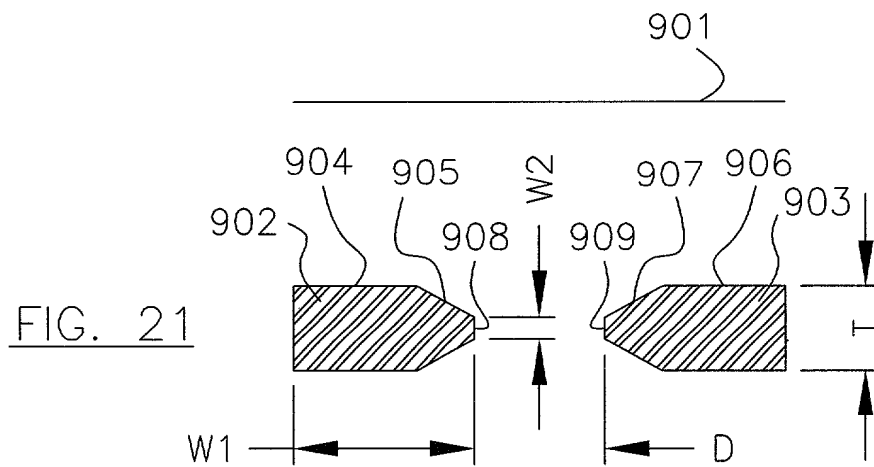


FIG. 22



FIG. 23



FIG. 24



FIG. 25



FIG. 26

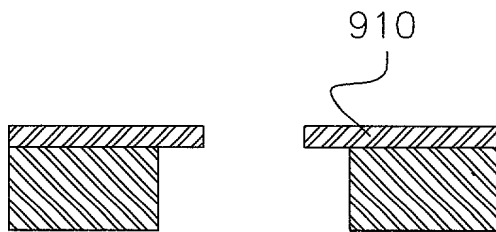


FIG. 27

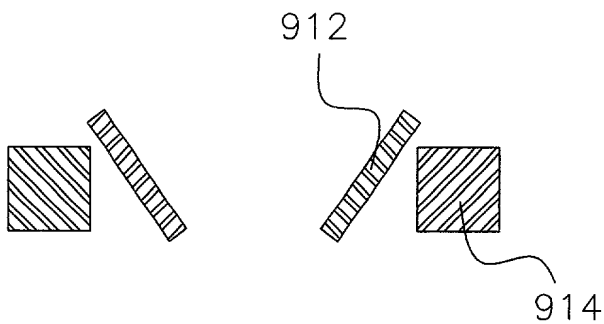


FIG. 28



FIG. 29



FIG. 30

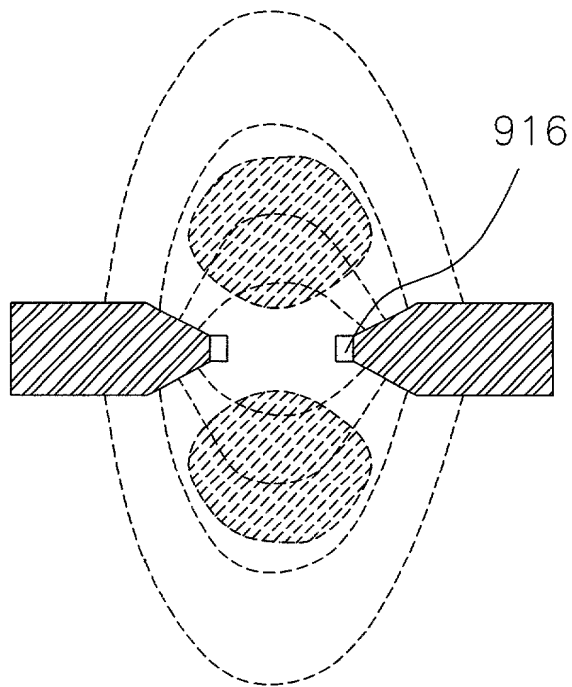


FIG. 31

